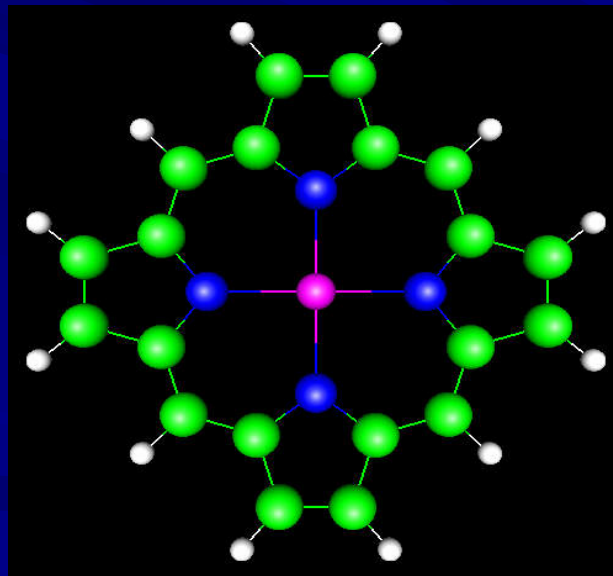


Methods for the Characterization of Porphyrin thin film dielectrics

Matthew Saucedo

Advisor: Dr. Jorge J. Santiago-Aviles



Picture from: <http://altair.physics.ncsu.edu/research.htm>

Background

■ What are Dielectrics?

Dielectrics are non-conducting material that have the ability to prevent electrical conduction, and at the same time are capable of absorbing electric charge.

■ Different Categories of Dielectrics

- Linear Dielectrics - $\mathbf{P} = \epsilon_0 \chi_e \mathbf{E}$
- Non – Linear dielectrics

Motivation

- Dielectrics are used to create capacitors which in turn tend to be very important voltage/energy sources
- Equation for Capacitance

$$C = \epsilon_r \epsilon_0 S/d$$

- High Energy Capacitors are implemented in the following
 - Pulse Powered Applications
 - Electrical vehicles, aircraft, and ships
 - Future Military Equipment

Research Goal

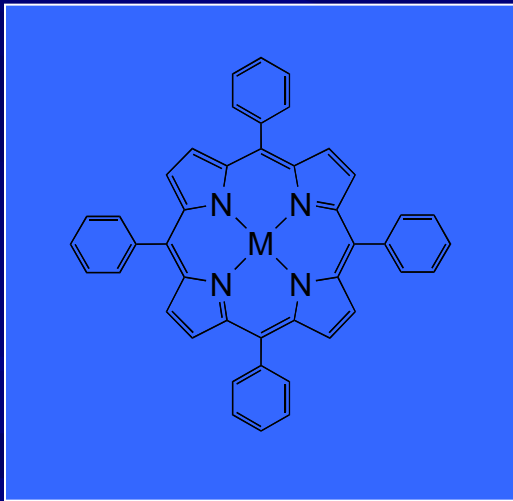
- Create different mixtures of ferroelectric particles with porphyrin to create high energy capacitors.

Project goals

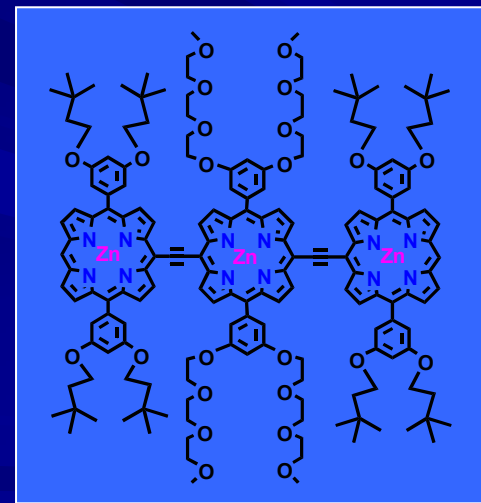
- Discover potential methods in characterizing porphyrin thin films
- Measure dielectric response of different samples of porphyrin

Porphyrin

- Organic Compounds that occur widely in nature
- Contain a central Metal Atom
- Exhibit high dielectric strengths, and are highly polarizable



Tetraphenylporphyrin
(TPP)



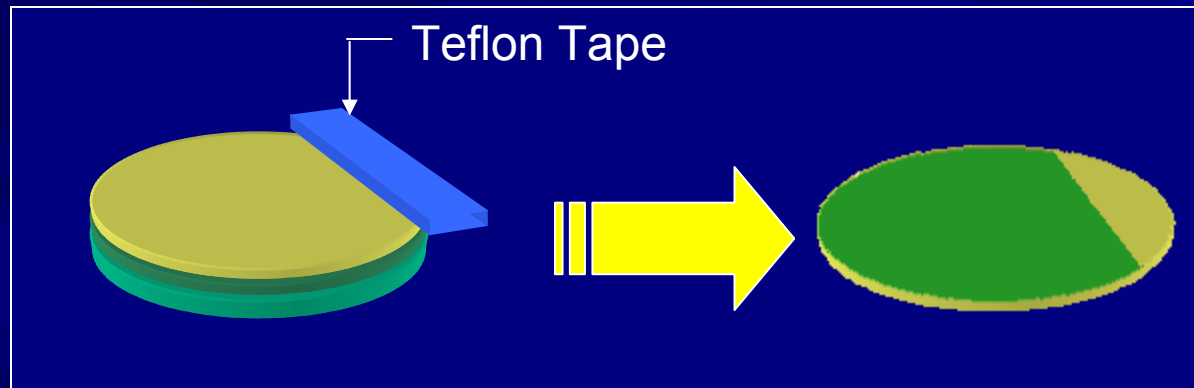
Ethyne-Bridged Porphyrin
Oligomers (DDD)

Methods

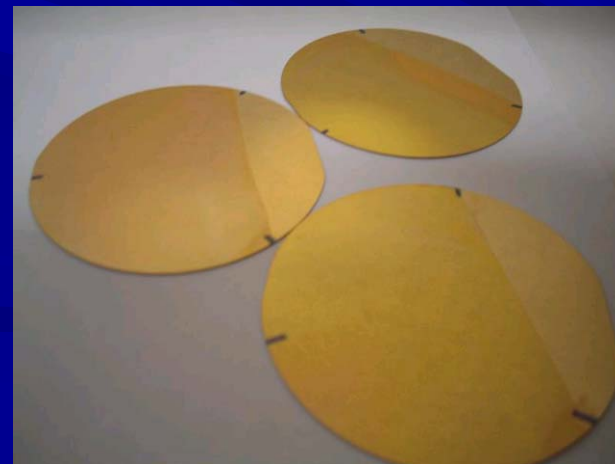
- Spin Coating, Capacitance device
- Indium Tin Oxide (ITO) Sandwich Cells, e-beam evaporation
- Photolithography

Spin Coating

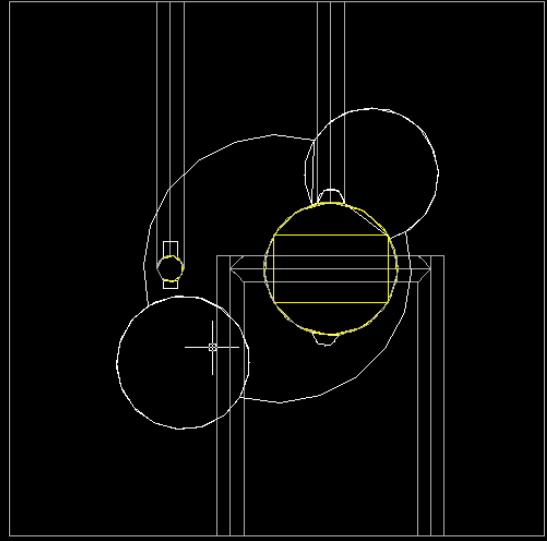
■ Wafer Process Flow (Spin Coating)



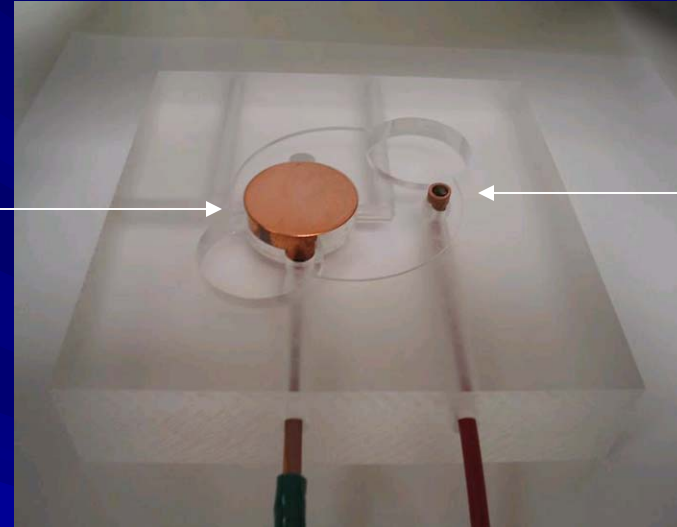
- Silicon substrate
- Silicon oxide
- Au (Gold)
- ZnTPP/ ZnDPP
polypropylene mixture



Capacitance Device



- Wafer is placed face down onto capacitance device
- Foam cushion is placed on back of wafer and a 100g weight establishes pressure

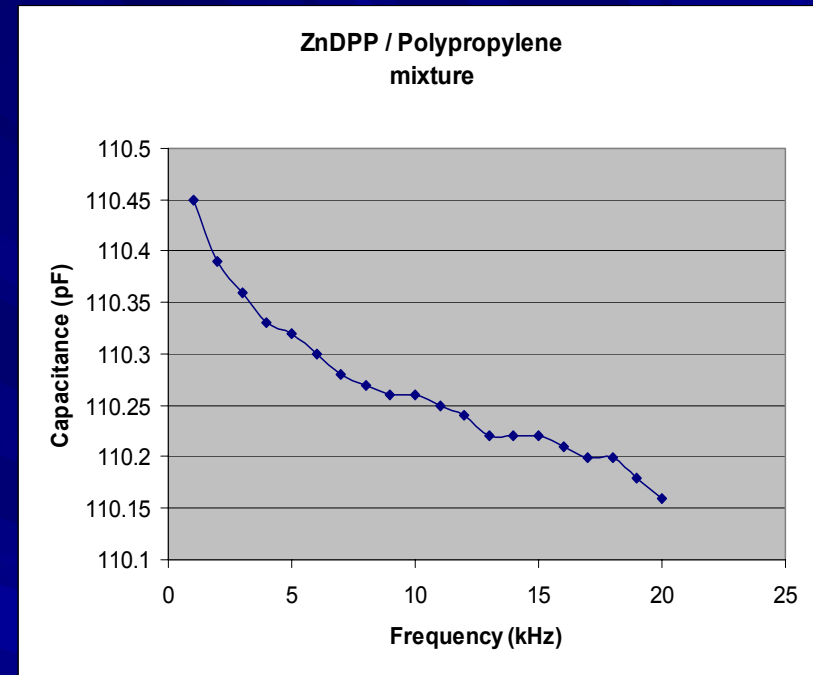
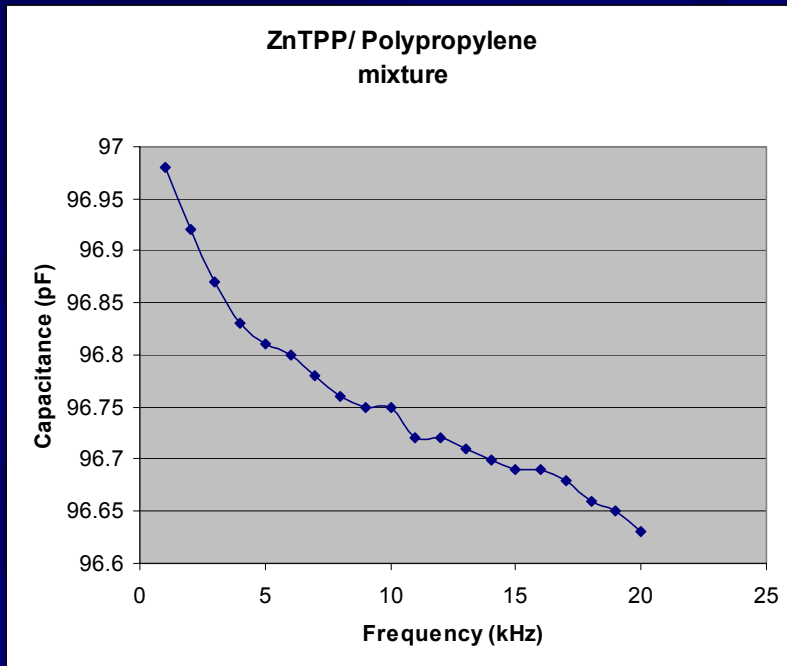


Connections to HPLCZ Meter

Springy Contact

Contact to Complete Capacitor

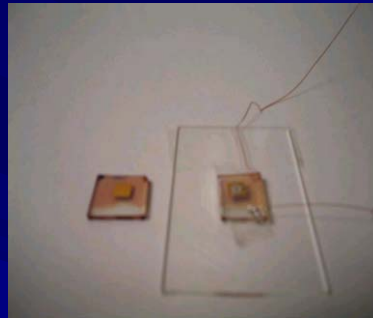
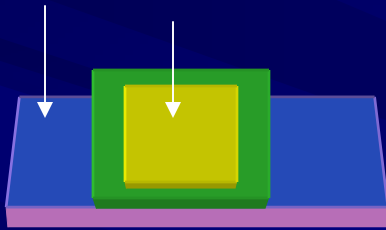
Discoveries



- Very low capacitance due to pressure established contacts
- Thickness not measured due to complications
- Estimate of thickness 800nm~1 micron, $\epsilon_{\text{mixture}} < 1$ unlikely

Indium tin oxide substrate

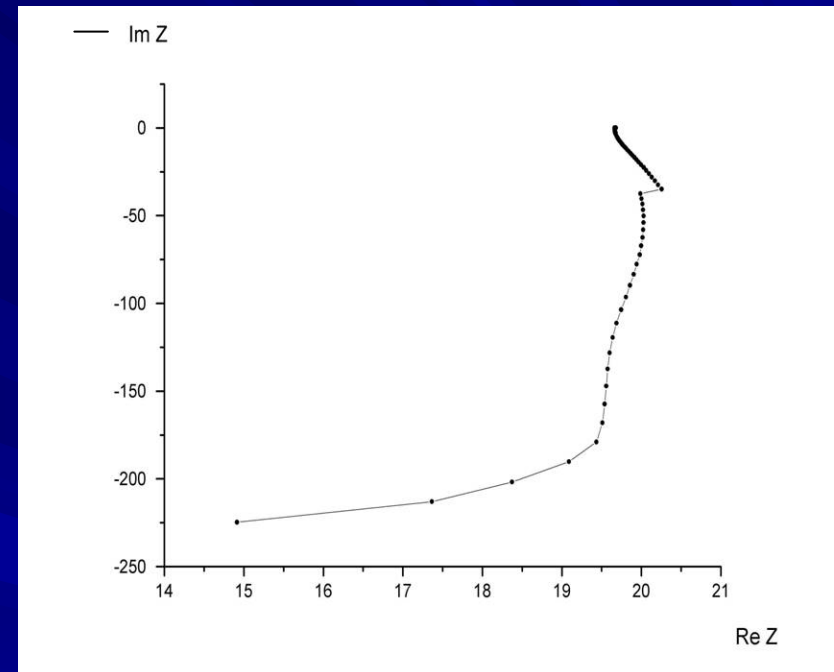
■ Indium tin oxide substrate
Contacts



■ Indium Tin Oxide Substrate

■ Porphyrin (ZnTPP)
(spin coating)

■ Gold contacts
(E-beam Evaporation)

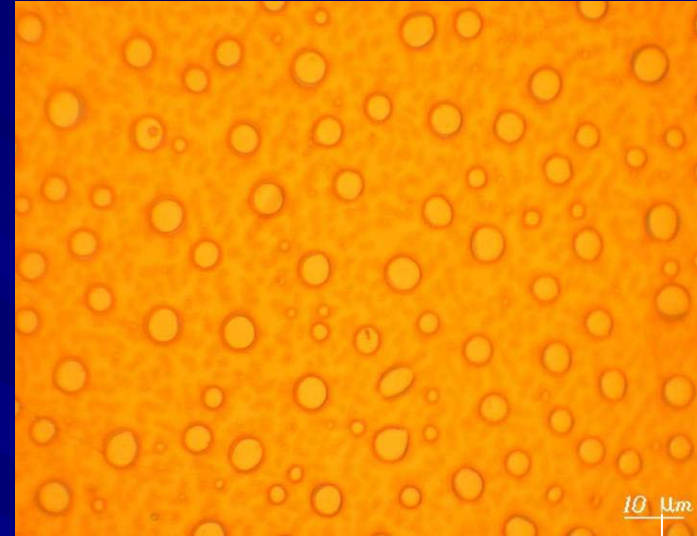


■ Shorts across Contacts

Discoveries



Zinc-diphenyl-porphyrin [10 μm]



Zn ethyne bridged trimer [10 μm]
(DDD)

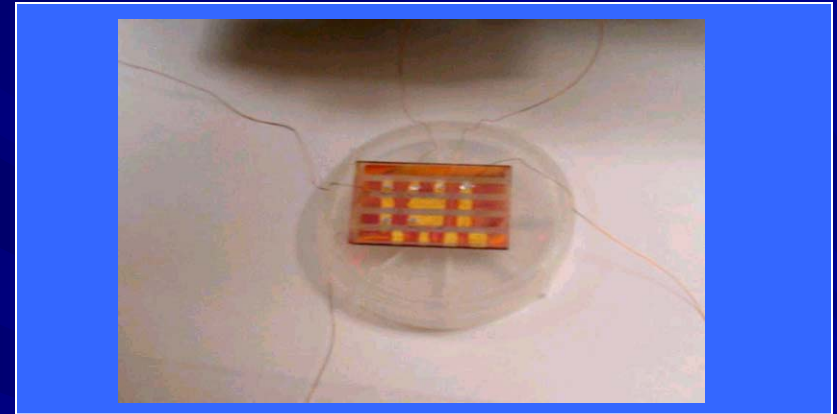
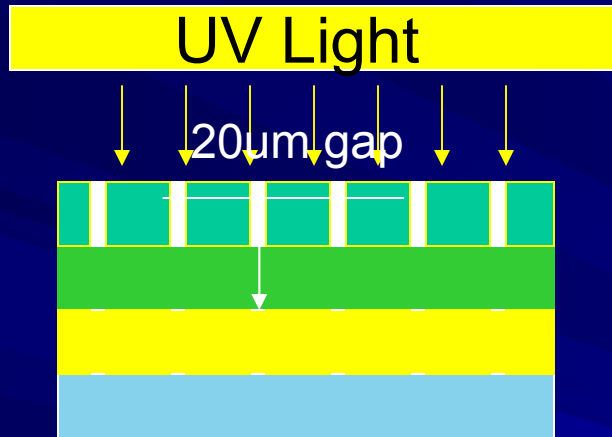
- Pinholes due to aggregates

- Non-Uniformity

- **Solutions performed**

- Explore different porphyrin media
- Explore Self Healing process of porphyrin

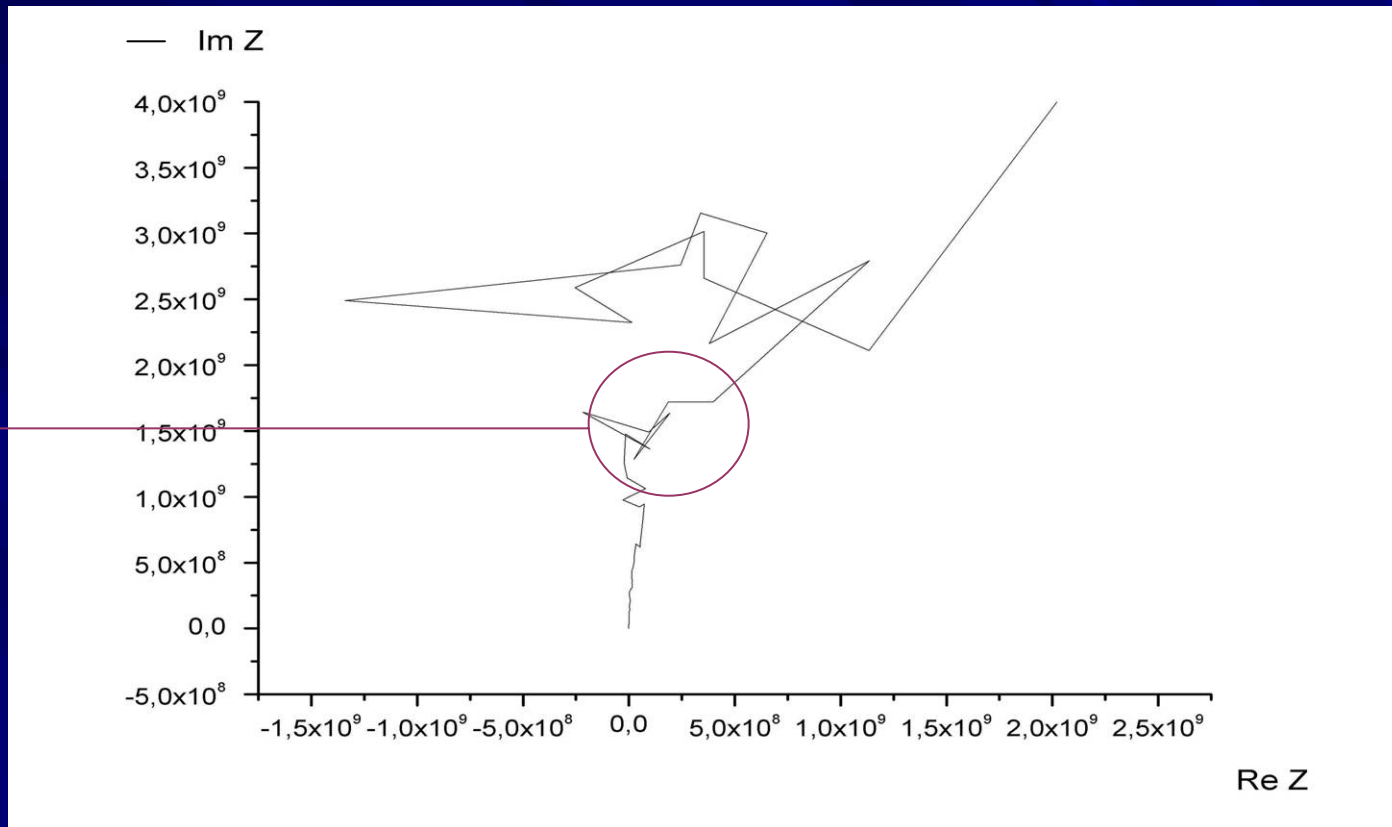
Photolithography



Dielectric covered substrate (ZnTPP)

-  Mask
-  Positive Resist
-  Au (Gold)
-  Glass Substrate

Photolithography contd.



- Out of range of equipment
- Capacitance normalized $\sim 4\text{pF}$ $\epsilon_r > 100$ (not likely)
- Theoretical calculations, $\epsilon_r \sim 10 \longrightarrow 3.32\text{fF}$

The Next Step

■ Creating uniform films

- Explore different solvents
- Use higher concentrations of porphyrin
(Even though it is an expensive process)
- Strengthen filtering during spin coating

■ Future Exploration

- Create different mixtures of ferroelectric particles with porphyrin

Acknowledgements

- NSF
- Dr. Jorge Santiago – Aviles
- Paul Frail
- Scott Slavin
- Maxim Nikiforov